PD-95727A

International Rectifier

IRF8915PbF

HEXFET® Power MOSFET

Applications

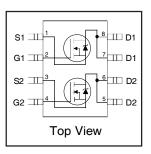
Dual SO-8 MOSFET for POL converters in desktop, servers, graphics cards, game consoles and set-top box

Lead-Free

V _{DSS}	R _{DS(on)} max	I _D	
20V	$18.3 \text{m}\Omega@V_{\text{GS}} = 10V$	8.9A	

Benefits

- Ultra-Low Gate Impedance
- Very Low R_{DS(on)}
- Fully Characterized Avalanche Voltage and Current





Absolute Maximum Ratings

	Parameter	Max.	Units
V _{DS}	Drain-to-Source Voltage	20	V
V _{GS}	Gate-to-Source Voltage	± 20	
I _D @ T _A = 25°C	Continuous Drain Current, V _{GS} @ 10V	8.9	
I _D @ T _A = 70°C	Continuous Drain Current, V _{GS} @ 10V	7.1	Α
I _{DM}	Pulsed Drain Current ①	71	
P _D @T _A = 25°C	Power Dissipation	2.0	W
P _D @T _A = 70°C	Power Dissipation	1.3	
	Linear Derating Factor	0.016	W/°C
T_J	Operating Junction and	-55 to + 150	°C
T _{STG}	Storage Temperature Range		

Thermal Resistance

	Parameter	Тур.	Max.	Units
$R_{\theta JL}$	Junction-to-Drain Lead		42	°C/W
$R_{\theta JA}$	Junction-to-Ambient ⁽⁴⁾		62.5	



Static @ $T_J = 25^{\circ}C$ (unless otherwise specified)

	Parameter	Min.	Тур.	Max.	Units	Conditions
BV _{DSS}	Drain-to-Source Breakdown Voltage	20			V	$V_{GS} = 0V, I_D = 250\mu A$
$\Delta \mathrm{BV}_{\mathrm{DSS}}/\Delta \mathrm{T}_{\mathrm{J}}$	Breakdown Voltage Temp. Coefficient		0.015		V/°C	Reference to 25°C, I _D = 1mA
R _{DS(on)}	Static Drain-to-Source On-Resistance		14.6	18.3	mΩ	V _{GS} = 10V, I _D = 8.9A ③
			21.6	27	1	V _{GS} = 4.5V, I _D = 7.1A ③
$V_{GS(th)}$	Gate Threshold Voltage	1.7		2.5	V	$V_{DS} = V_{GS}$, $I_D = 250\mu A$
$\Delta V_{GS(th)}/\Delta T_J$	Gate Threshold Voltage Coefficient		-4.8		mV/°C	
I _{DSS}	Drain-to-Source Leakage Current			1.0	μΑ	$V_{DS} = 16V, V_{GS} = 0V$
				150		$V_{DS} = 16V, V_{GS} = 0V, T_{J} = 125^{\circ}C$
I _{GSS}	Gate-to-Source Forward Leakage			100	nA	V _{GS} = 20V
	Gate-to-Source Reverse Leakage			-100	1	V _{GS} = -20V
gfs	Forward Transconductance	12			S	$V_{DS} = 10V, I_D = 7.1A$
Q_g	Total Gate Charge		4.9	7.4		
Q _{gs1}	Pre-Vth Gate-to-Source Charge		1.8		1	$V_{DS} = 10V$
Q _{gs2}	Post-Vth Gate-to-Source Charge		0.61		nC	$V_{GS} = 4.5V$
Q_{gd}	Gate-to-Drain Charge		1.7			$I_D = 7.1A$
Q_{godr}	Gate Charge Overdrive		0.79		1	See Fig. 6
Q _{sw}	Switch Charge (Q _{gs2} + Q _{gd})		2.3		1	
Q _{oss}	Output Charge		2.7		nC	$V_{DS} = 10V, V_{GS} = 0V$
t _{d(on)}	Turn-On Delay Time		6.0			$V_{DD} = 4.5V, V_{GS} = 4.5V$
t _r	Rise Time		12		ns	$I_D = 7.1A$
t _{d(off)}	Turn-Off Delay Time		7.1		1	Clamped Inductive Load
t _f	Fall Time	_	3.6		1	
C _{iss}	Input Capacitance	_	540			V _{GS} = 0V
C _{oss}	Output Capacitance		180		pF	$V_{DS} = 10V$
C _{rss}	Reverse Transfer Capacitance		91		[f = 1.0MHz

Avalanche Characteristics

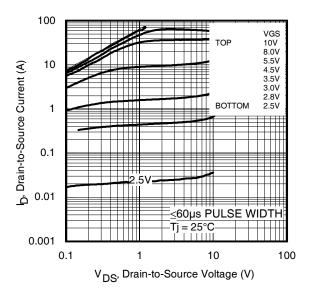
	Parameter	Тур.	Max.	Units
E _{AS}	Single Pulse Avalanche Energy ②		15	mJ
I _{AR}	Avalanche Current ①		7.1	Α

Diode Characteristics

	Parameter	Min.	Тур.	Max.	Units	Conditions
Is	Continuous Source Current			2.5		MOSFET symbol
	(Body Diode)				Α	showing the
I _{SM}	Pulsed Source Current			71		integral reverse
	(Body Diode) ①					p-n junction diode.
V_{SD}	Diode Forward Voltage			1.0	V	$T_J = 25^{\circ}C$, $I_S = 7.1A$, $V_{GS} = 0V$ ③
t _{rr}	Reverse Recovery Time		13	19	ns	$T_J = 25$ °C, $I_F = 7.1$ A, $V_{DD} = 10$ V
Q _{rr}	Reverse Recovery Charge		3.5	5.2	nC	di/dt = 100A/µs ③

International TOR Rectifier

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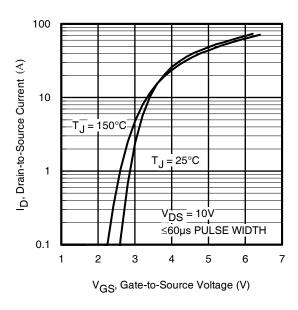
100

(Y) tuesure 10

Output 10

Fig 1. Typical Output Characteristics

Fig 2. Typical Output Characteristics



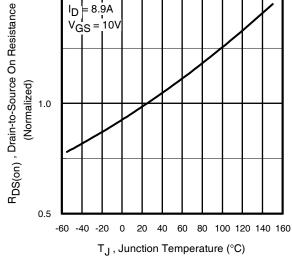
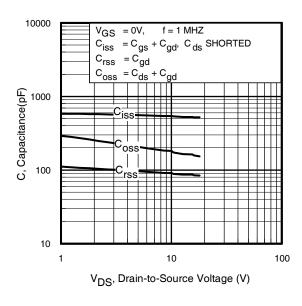


Fig 3. Typical Transfer Characteristics

Fig 4. Normalized On-Resistance vs. Temperature

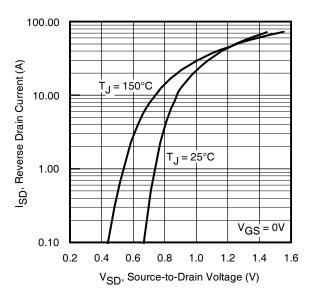
International TOR Rectifier



6.0 I_D= 7.1A _V_{DS}= 16V V_{GS}, Gate-to-Source Voltage (V) 5.0 V_{DS} = 10V 4.0 3.0 2.0 1.0 0.0 2 5 7 0 3 4 6 Q_G Total Gate Charge (nC)

Fig 5. Typical Capacitance vs. Drain-to-Source Voltage

Fig 6. Typical Gate Charge Vs. Gate-to-Source Voltage



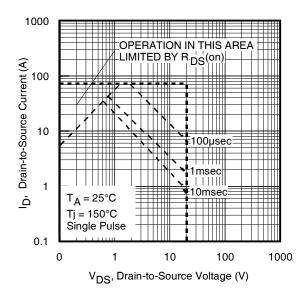
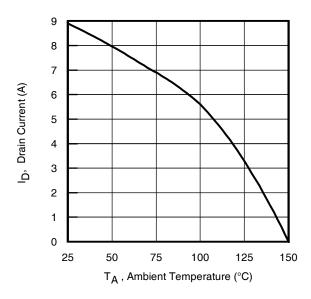


Fig 7. Typical Source-Drain Diode Forward Voltage

Fig 8. Maximum Safe Operating Area



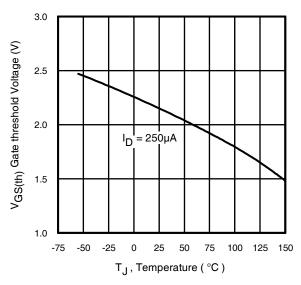


Fig 9. Maximum Drain Current vs. Ambient Temperature

Fig 10. Threshold Voltage vs. Temperature

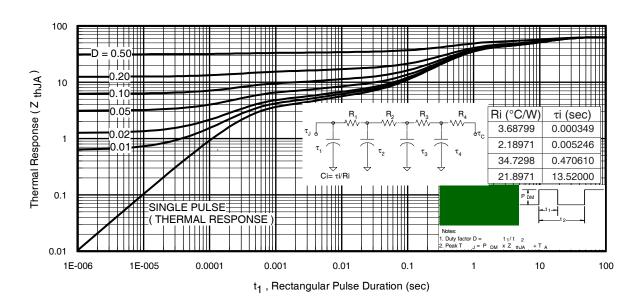


Fig 11. Maximum Effective Transient Thermal Impedance, Junction-to-Ambient

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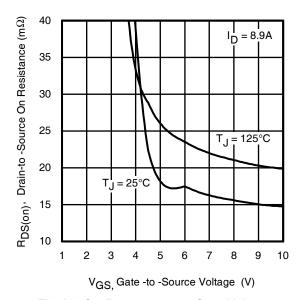


Fig 12. On-Resistance vs. Gate Voltage

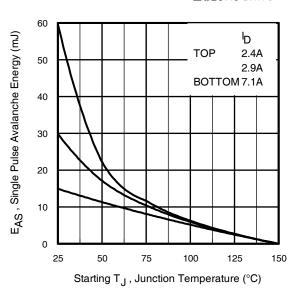


Fig 13. Maximum Avalanche Energy vs. Drain Current

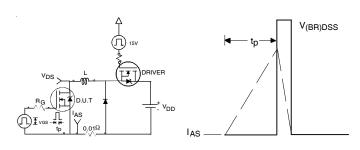


Fig 14. Unclamped Inductive Test Circuit and Waveform

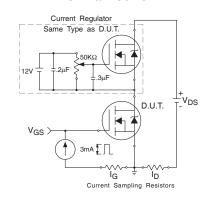


Fig 15. Gate Charge Test Circuit

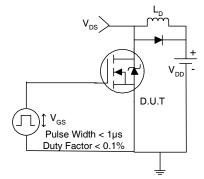


Fig 16. Switching Time Test Circuit

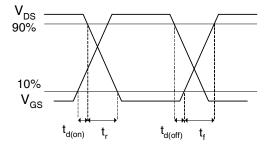


Fig 17. Switching Time Waveforms

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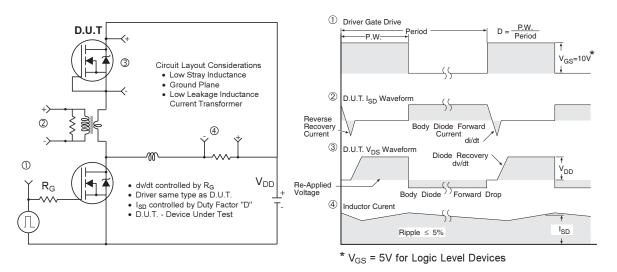


Fig 15. Peak Diode Recovery dv/dt Test Circuit for N-Channel HEXFET® Power MOSFETs

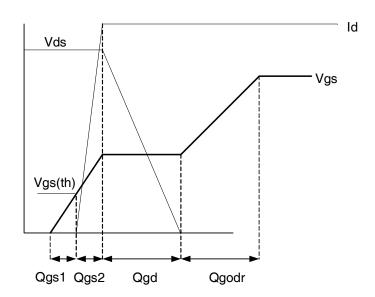


Fig 16. Gate Charge Waveform

Power MOSFET Selection for Non-Isolated DC/DC Converters

Control FET

Special attention has been given to the power losses in the switching elements of the circuit - Q1 and Q2. Power losses in the high side switch Q1, also called the Control FET, are impacted by the $R_{\rm ds(on)}$ of the MOSFET, but these conduction losses are only about one half of the total losses.

Power losses in the control switch Q1 are given by;

$$P_{loss} = P_{conduction} + P_{switching} + P_{drive} + P_{output}$$

This can be expanded and approximated by:

$$\begin{split} P_{loss} &= \left(I_{rms}^{2} \times R_{ds(on)}\right) \\ &+ \left(I \times \frac{Q_{gd}}{i_{g}} \times V_{in} \times f\right) + \left(I \times \frac{Q_{gs2}}{i_{g}} \times V_{in} \times f\right) \\ &+ \left(Q_{g} \times V_{g} \times f\right) \\ &+ \left(\frac{Q_{oss}}{2} \times V_{in} \times f\right) \end{split}$$

This simplified loss equation includes the terms ${\rm Q_{gs2}}$ and ${\rm Q_{oss}}$ which are new to Power MOSFET data sheets.

 Q_{gs2} is a sub element of traditional gate-source charge that is included in all MOSFET data sheets. The importance of splitting this gate-source charge into two sub elements, Q_{gs1} and Q_{gs2} , can be seen from Fig 16.

 $\rm Q_{gs2}$ indicates the charge that must be supplied by the gate driver between the time that the threshold voltage has been reached and the time the drain current rises to $\rm I_{dmax}$ at which time the drain voltage begins to change. Minimizing $\rm Q_{gs2}$ is a critical factor in reducing switching losses in Q1.

 $\rm Q_{oss}$ is the charge that must be supplied to the output capacitance of the MOSFET during every switching cycle. Figure A shows how $\rm Q_{oss}$ is formed by the parallel combination of the voltage dependant (nonlinear) capacitance's $\rm C_{ds}$ and $\rm C_{dg}$ when multiplied by the power supply input buss voltage.

Synchronous FET

The power loss equation for Q2 is approximated by;

$$\begin{split} P_{loss} &= P_{conduction} + P_{drive} + P_{output}^* \\ P_{loss} &= \left(I_{rms}^2 \times R_{ds(on)}\right) \\ &+ \left(Q_g \times V_g \times f\right) \\ &+ \left(\frac{Q_{oss}}{2} \times V_{in} \times f\right) + \left(Q_{rr} \times V_{in} \times f\right) \end{split}$$

*dissipated primarily in Q1.

For the synchronous MOSFET Q2, $R_{\text{ds(on)}}$ is an important characteristic; however, once again the importance of gate charge must not be overlooked since it impacts three critical areas. Under light load the MOSFET must still be turned on and off by the control IC so the gate drive losses become much more significant. Secondly, the output charge Q_{oss} and reverse recovery charge Q_{r} both generate losses that are transfered to Q1 and increase the dissipation in that device. Thirdly, gate charge will impact the MOSFETs' susceptibility to Cdv/dt turn on.

The drain of Q2 is connected to the switching node of the converter and therefore sees transitions between ground and $V_{\rm in}$. As Q1 turns on and off there is a rate of change of drain voltage dV/dt which is capacitively coupled to the gate of Q2 and can induce a voltage spike on the gate that is sufficient to turn the MOSFET on, resulting in shoot-through current . The ratio of $Q_{\rm gd}/Q_{\rm gs1}$ must be minimized to reduce the potential for Cdv/dt turn on.

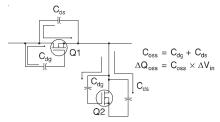


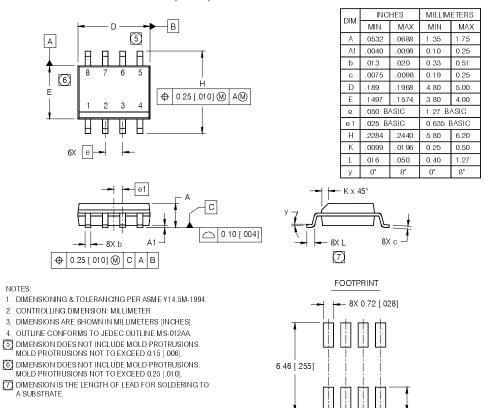
Figure A: Q ... Characteristic

NOTES:

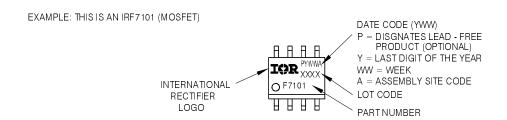
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SO-8 Package Outline(Mosfet & Fetky)

Dimensions are shown in milimeters (inches)



SO-8 Part Marking Information



3X 1.27 [.050] -

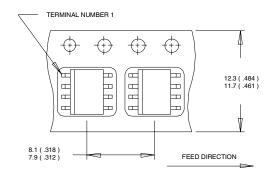
8X 1.78 [.070]

Note: For the most current drawing please refer to IR website at: http://www.irf.com/package/ www.irf.com

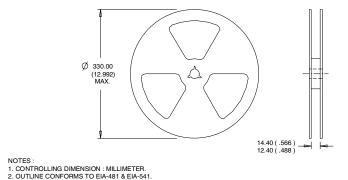
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SO-8 Tape and Reel

Dimensions are shown in millimeters (inches)



- CONTROLLING DIMENSION: MILLIMETER.
 ALL DIMENSIONS ARE SHOWN IN MILLIMETERS(INCHES).
 OUTLINE CONFORMS TO EIA-481 & EIA-541.



Note: For the most current drawing please refer to IR website at http://www.irf.com/package/

Notes:

- ① Repetitive rating; pulse width limited by max. junction temperature. ② Starting $T_J = 25$ °C, L = 0.59mH, $R_G = 25\Omega$, $I_{AS} = 7.1$ A.
- ③ Pulse width $\leq 400\mu s$; duty cycle $\leq 2\%$.
- When mounted on 1 inch square copper board.
- $\$ R₀ is measured at T_J of approximately 90°C.

Data and specifications subject to change without notice. This product has been designed and qualified for the Consumer market. Qualifications Standards can be found on IR's Web site.



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